•	<i>Searcn</i>	Notes

Application/Control No.	Applicant(s)/Patent under Reexamination	
10/658,466	SHIRAISHI ET AL.	
Examiner	Art Unit	
Jacon I. Jazorojk	1731	

	SEAR	CHED	
Class	Subclass	Date	Examiner
		,	
-			
•			

INT	ERFERENC	E SEARCH	ED
Class	Subclass	Date	Examiner
		-	
		<u>. </u>	

SEARCH NOT (INCLUDING SEARCH) .
	DATE	EXMR
Inventor search completed: -Shiraishi, Koichiro - OHMI, SHIGEAKI	4/24/2006	JLL
65/24,26,30.1,60.1,60.3,60.6,60.3,64, 111,102,374.15 427/450,535,539,577,165 (* limited by key word per Search History)	4/25/2006	JLL
Discussion with Examiner Queenie Dehghan on inherency and USC 102	4/25/2006	JLL
EAST Search (See search history)	4/25/2006	JLL
Updated EAST Search	11/10/2006	JLL